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Sommario/riassunto

This book presents the select proceedings of the 9th National Conference on Advances in Metrology (AdMet 2024). It highlights and discusses the recent technological advancements and developments in the areas of fundamental and quantum metrology, physico-mechanical and electrical metrology, time and frequency metrology, materials metrology, industrial and legal metrology, and digital metrology, gas and aerosol metrology among others. This book is aimed at those engaged in conformity assessment, quality system management, calibration, and testing in all sectors of industry as well as in academic research. The book is a valuable reference for metrologists, scientists, engineers, academicians, and students from research institutes and industrial establishments to explore future directions and research in the areas of sensors, advanced materials, measurements, and quality improvement.